



10/8/10

**RELIABILITY MONITOR REPORT
FOR**

X3 0.4 μ m Silicon Gate CMOS (S45)

MAXIM Integrated Products

120 San Gabriel Dr.
Sunnyvale, CA 94086

**This Report was prepared by
Maxim Reliability Engineering**

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX11046ETN+	MAX11080GUU	MAX16814ATP/	MAX16814UUP	MAX16922ATPF
MAXQ314				

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 19284 QUANTITY: 298 FAILS: 0 FITS: 5.9

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 10/1/2009 and 9/30/2010 .

Process Information:

Process Description: X3 0.4µm Silicon Gate CMOS (S45)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	0817	MAX11046ETN+	135C	211 HRS	50	0	SHZZBQ002BQ
HIGH TEMP OP LIFE	0920	MAX16814UUP+	135C	138 HRS	31	0	SUPZCQ003CR
HIGH TEMP OP LIFE	0924	MAX11080GUU+	135C	324 HRS	47	0	SMZZEQ003A#
HIGH TEMP OP LIFE	0932	MAXQ314	125C, 3.6 VOLTS	192 HRS	45	0	QJ991300AB
HIGH TEMP OP LIFE	0938	MAX16922ATPF/V+	135C	700 HRS	80	0	SRAZDQ003AD
HIGH TEMP OP LIFE	0952	MAX11080GUU+	135C	192 HRS	45	0	SMZZFA004EB
Total:						0	

STORAGE LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
STORAGE LIFE	0924	MAX11080GUU+	150C	500 HRS	44	0	SMZZEQ003A#
STORAGE LIFE	1026	MAX16814ATP/V+	150C	1000 HRS	50	0	SUPZC3051B#
Total:						0	

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